

# MOSFET

Metal Oxide Semiconductor Field Effect Transistor

## OptiMOS™

OptiMOS™3 Power-Transistor, 100 V  
IPT020N10N3

## Data Sheet

Rev. 2.0  
Final

Power Management & Multimarket

## 1 Description

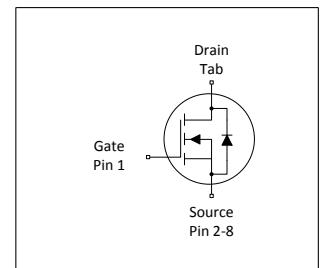
### Features

- N-channel, normal level
- Excellent gate charge x  $R_{DS(on)}$  product (FOM)
- Extremely low on-resistance  $R_{DS(on)}$
- High current capability
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC <sup>1)</sup> for target application
- Halogen-free according to IEC61249-2-21



**Table 1 Key Performance Parameters**

| Parameter        | Value | Unit |
|------------------|-------|------|
| $V_{DS}$         | 100   | V    |
| $R_{DS(on),max}$ | 2     | mΩ   |
| $I_D$            | 300   | A    |



| Type / Ordering Code | Package     | Marking  | Related Links |
|----------------------|-------------|----------|---------------|
| IPT020N10N3          | PG-HSOF-8-1 | 020N10N3 | -             |

<sup>1)</sup> J-STD20 and JESD22

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## 2 Maximum ratings

at  $T_j = 25\text{ °C}$ , unless otherwise specified

**Table 2 Maximum ratings**

| Parameter                          | Symbol         | Values |      |            | Unit | Note / Test Condition                                   |
|------------------------------------|----------------|--------|------|------------|------|---|
|                                    |                | Min.   | Typ. | Max.       |      |   |
| Continuous drain current           | $I_D$          | -      | -    | 300<br>212 | A    | $T_C=25\text{ °C}$ <sup>1)</sup><br>$T_C=100\text{ °C}$ |
| Pulsed drain current <sup>1)</sup> | $I_{D,pulse}$  | -      | -    | 1200       | A    | $T_C=25\text{ °C}$                                      |
| Avalanche energy, single pulse     | $E_{AS}$       | -      | -    | 800        | mJ   | $I_D=150\text{ A}$ , $R_{GS}=25\text{ }\Omega$          |
| Gate source voltage                | $V_{GS}$       | -20    | -    | 20         | V    | -   |
| Power dissipation                  | $P_{tot}$      | -      | -    | 375        | W    | $T_C=25\text{ °C}$                                      |
| Operating and storage temperature  | $T_j, T_{stg}$ | -55    | -    | 175        | °C   | IEC climatic category;<br>DIN IEC 68-1: 55/175/56       |

## 3 Thermal characteristics

**Table 3 Thermal characteristics**

| Parameter   | Symbol     | Values |      |      | Unit | Note / Test Condition |
|---|------------|--------|------|------|------|-----------------------|
|   |            | Min.   | Typ. | Max. |      |                       |
| Thermal resistance junction - case  | $R_{thJC}$ | -      | 0.2  | 0.4  | K/W  | -                     |
| Thermal resistance junction - ambient, minimal footprint                            | $R_{thJA}$ | -      | -    | 62   | K/W  | -                     |
| Thermal resistance junction - ambient, 6 cm <sup>2</sup> cooling area <sup>2)</sup> | $R_{thJA}$ | -      | -    | 40   | K/W  | -                     |

<sup>1)</sup> See figure 3

<sup>2)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

## 4 Electrical characteristics

**Table 4 Static characteristics**

| Parameter                        | Symbol        | Values |            |          | Unit             | Note / Test Condition   |
|----------------------------------|---------------|--------|------------|----------|------------------|---|
|                                  |               | Min.   | Typ.       | Max.     |                  |   |
| Drain-source breakdown voltage   | $V_{(BR)DSS}$ | 100    | -          | -        | V                | $V_{GS}=0\text{ V}$ , $I_D=1\text{ mA}$   |
| Gate threshold voltage           | $V_{GS(th)}$  | 2      | 2.7        | 3.5      | V                | $V_{DS}=V_{GS}$ , $I_D=272\text{ }\mu\text{A}$  |
| Zero gate voltage drain current  | $I_{DSS}$     | -      | 0.1<br>10  | 1<br>100 | $\mu\text{A}$    | $V_{DS}=100\text{ V}$ , $V_{GS}=0\text{ V}$ , $T_j=25\text{ }^\circ\text{C}$<br>$V_{DS}=100\text{ V}$ , $V_{GS}=0\text{ V}$ , $T_j=125\text{ }^\circ\text{C}$ |
| Gate-source leakage current      | $I_{GSS}$     | -      | 1          | 100      | nA               | $V_{GS}=20\text{ V}$ , $V_{DS}=0\text{ V}$  |
| Drain-source on-state resistance | $R_{DS(on)}$  | -      | 1.7<br>2.2 | 2<br>3.7 | $\text{m}\Omega$ | $V_{GS}=10\text{ V}$ , $I_D=150\text{ A}$<br>$V_{GS}=6\text{ V}$ , $I_D=75\text{ A}$ ,  |
| Gate resistance                  | $R_G$         | -      | 1.9        | 2.9      | $\Omega$         | -   |
| Transconductance                 | $g_{fs}$      | 125    | 250        | -        | S                | $ V_{DS} >2 I_D /R_{DS(on)max}$ , $I_D=150\text{ A}$  |

**Table 5 Dynamic characteristics**

| Parameter                    | Symbol       | Values |       |       | Unit | Note / Test Condition   |
|------------------------------|--------------|--------|-------|-------|------|---|
|                              |              | Min.   | Typ.  | Max.  |      |   |
| Input capacitance            | $C_{iss}$    | -      | 11200 | 14896 | pF   | $V_{GS}=0\text{ V}$ , $V_{DS}=50\text{ V}$ , $f=1\text{ MHz}$                                       |
| Output capacitance           | $C_{oss}$    | -      | 2010  | 2673  | pF   | $V_{GS}=0\text{ V}$ , $V_{DS}=50\text{ V}$ , $f=1\text{ MHz}$                                       |
| Reverse transfer capacitance | $C_{riss}$   | -      | 69    | 138   | pF   | $V_{GS}=0\text{ V}$ , $V_{DS}=50\text{ V}$ , $f=1\text{ MHz}$                                       |
| Turn-on delay time           | $t_{d(on)}$  | -      | 34    | -     | ns   | $V_{DD}=50\text{ V}$ , $V_{GS}=10\text{ V}$ , $I_D=100\text{ A}$ ,<br>$R_{G,ext}=1.6\text{ }\Omega$ |
| Rise time                    | $t_r$        | -      | 58    | -     | ns   | $V_{DD}=50\text{ V}$ , $V_{GS}=10\text{ V}$ , $I_D=100\text{ A}$ ,<br>$R_{G,ext}=1.6\text{ }\Omega$ |
| Turn-off delay time          | $t_{d(off)}$ | -      | 84    | -     | ns   | $V_{DD}=50\text{ V}$ , $V_{GS}=10\text{ V}$ , $I_D=100\text{ A}$ ,<br>$R_{G,ext}=1.6\text{ }\Omega$ |
| Fall time                    | $t_f$        | -      | 18    | -     | ns   | $V_{DD}=50\text{ V}$ , $V_{GS}=10\text{ V}$ , $I_D=100\text{ A}$ ,<br>$R_{G,ext}=1.6\text{ }\Omega$ |

**Table 6 Gate charge characteristics <sup>1)</sup>**

| Parameter             | Symbol        | Values |      |      | Unit | Note / Test Condition  |
|-----------------------|---------------|--------|------|------|------|--|
|                       |               | Min.   | Typ. | Max. |      |  |
| Gate to source charge | $Q_{gs}$      | -      | 48   | -    | nC   | $V_{DD}=50\text{ V}$ , $I_D=100\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Gate to drain charge  | $Q_{gd}$      | -      | 27   | -    | nC   | $V_{DD}=50\text{ V}$ , $I_D=100\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Switching charge      | $Q_{sw}$      | -      | 42   | -    | nC   | $V_{DD}=50\text{ V}$ , $I_D=100\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Gate charge total     | $Q_g$         | -      | 156  | 207  | nC   | $V_{DD}=50\text{ V}$ , $I_D=100\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Gate plateau voltage  | $V_{plateau}$ | -      | 4.3  | -    | V    | $V_{DD}=50\text{ V}$ , $I_D=100\text{ A}$ , $V_{GS}=0\text{ to }10\text{ V}$ |
| Output charge         | $Q_{oss}$     | -      | 55   | -    | nC   | $V_{DD}=50\text{ V}$ , $V_{GS}=0\text{ V}$                                   |

<sup>1)</sup> See "Gate charge waveforms" for parameter definition

**Table 7 Reverse diode**

| Parameter                        | Symbol        | Values |      |      | Unit | Note / Test Condition  |
|----------------------------------|---------------|--------|------|------|------|--|
|                                  |               | Min.   | Typ. | Max. |      |  |
| Diode continuous forward current | $I_S$         | -      | -    | 300  | A    | $T_C=25\text{ °C}$   |
| Diode pulse current              | $I_{S,pulse}$ | -      | -    | 1200 | A    | $T_C=25\text{ °C}$   |
| Diode forward voltage            | $V_{SD}$      | -      | 0.89 | 1    | V    | $V_{GS}=0\text{ V}, I_F=150\text{ A}, T_J=25\text{ °C}$      |
| Reverse recovery time            | $t_{rr}$      | -      | 86   | 172  | ns   | $V_R=50\text{ V}, I_F=I_S, di_F/dt=100\text{ A}/\mu\text{s}$ |
| Reverse recovery charge          | $Q_{rr}$      | -      | 232  | -    | nC   | $V_R=50\text{ V}, I_F=I_S, di_F/dt=100\text{ A}/\mu\text{s}$ |

## 5 Electrical characteristics diagrams

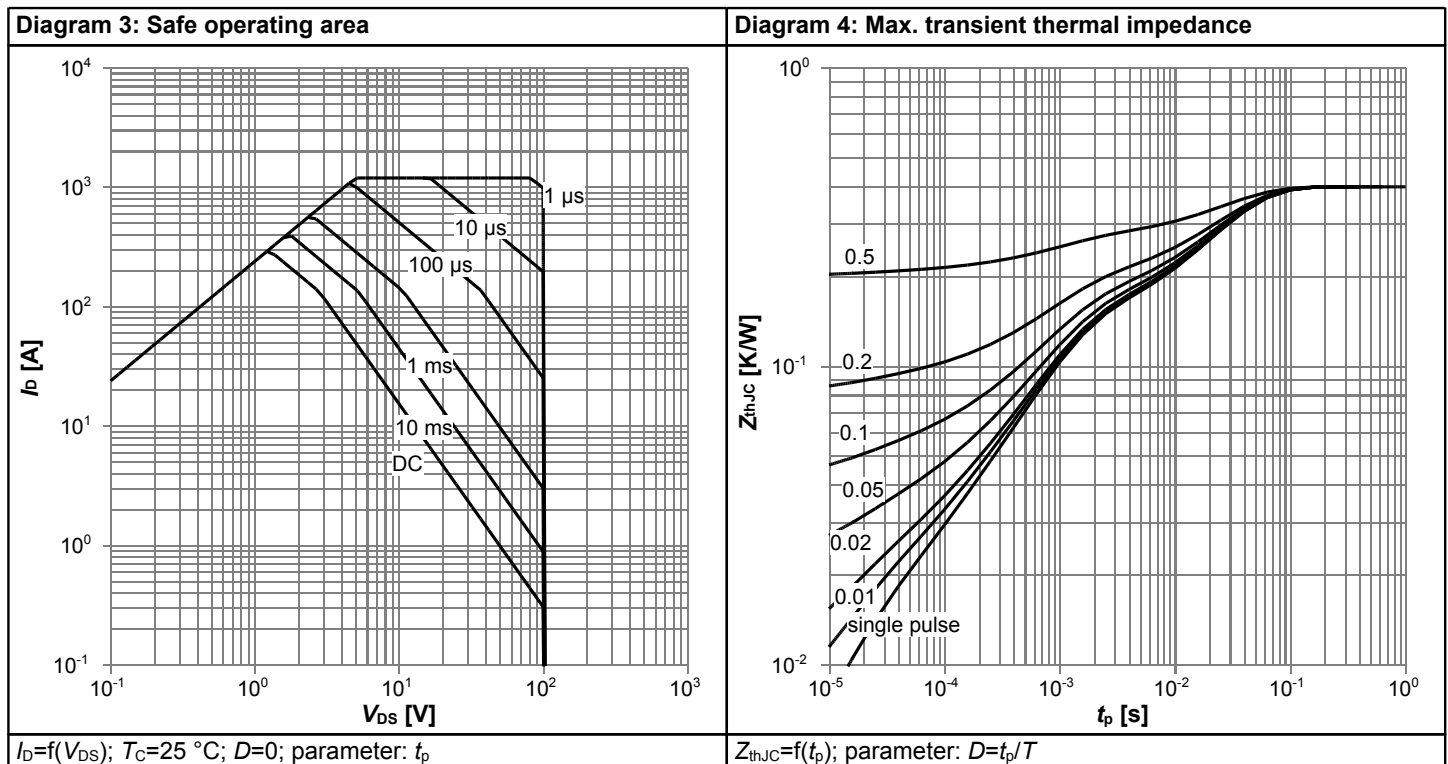
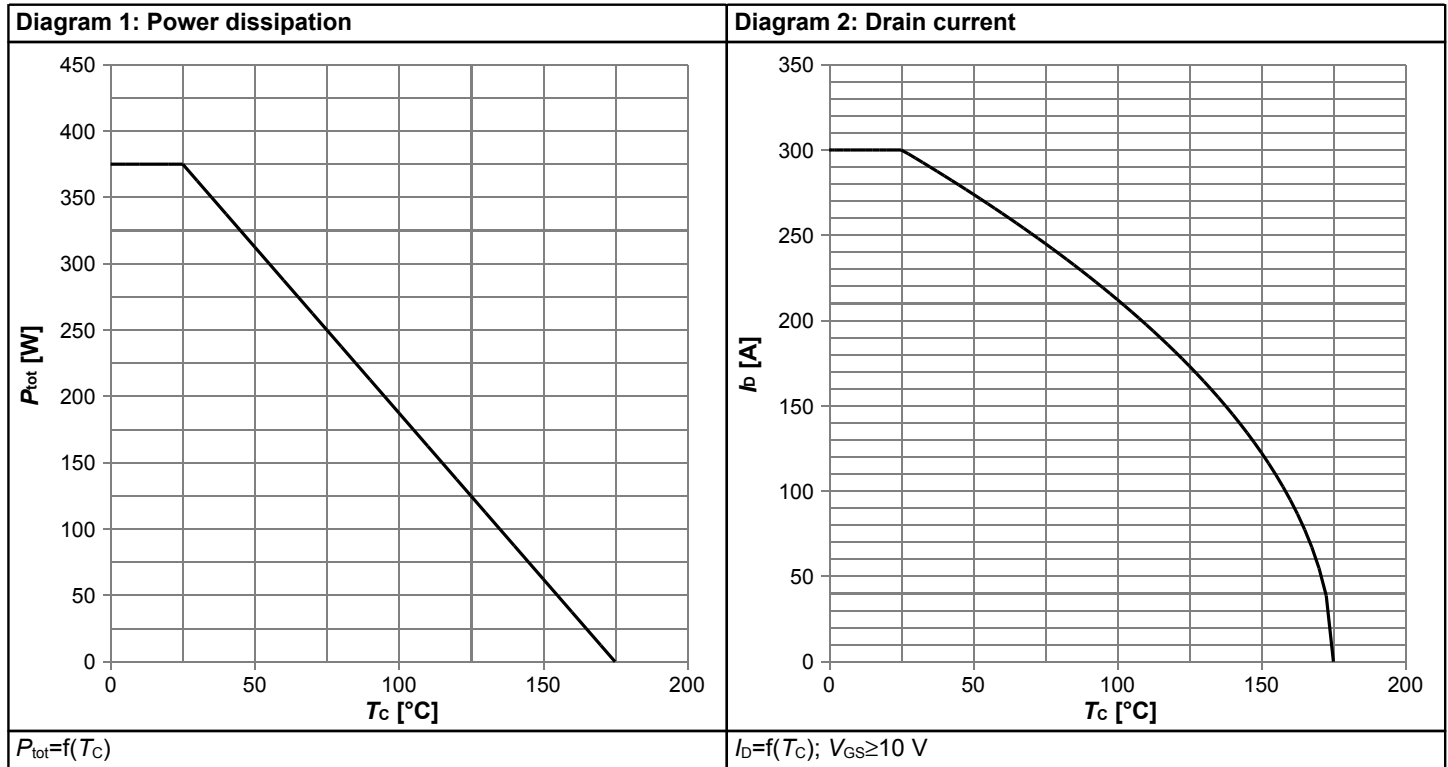
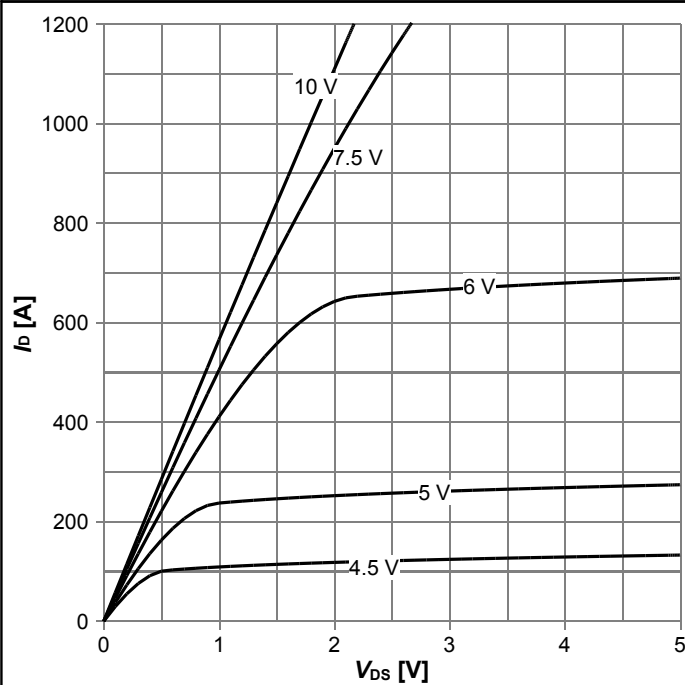
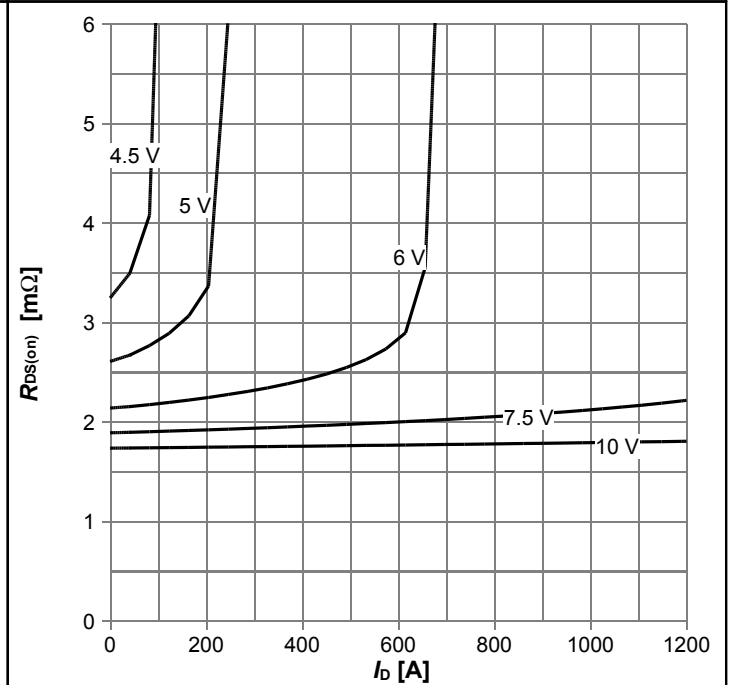


Diagram 5: Typ. output characteristics



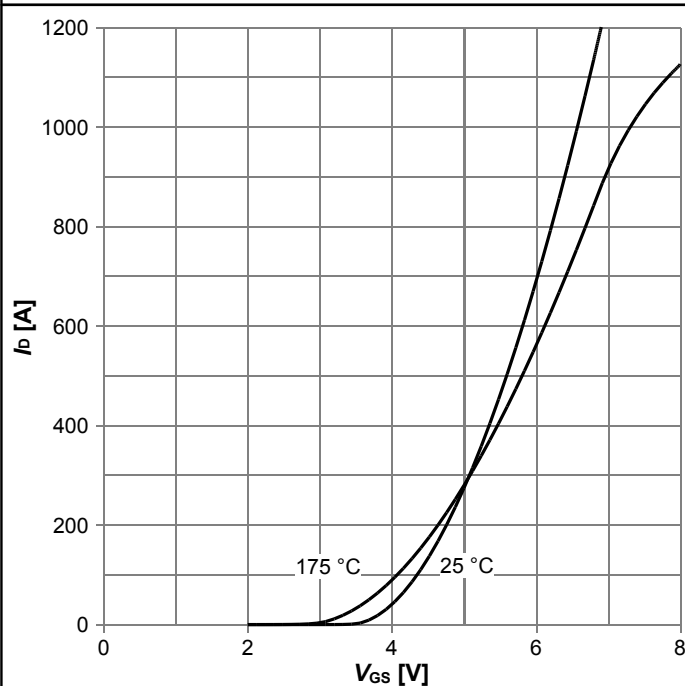
$I_D = f(V_{DS}); T_j = 25\text{ °C};$  parameter:  $V_{GS}$

Diagram 6: Typ. drain-source on resistance



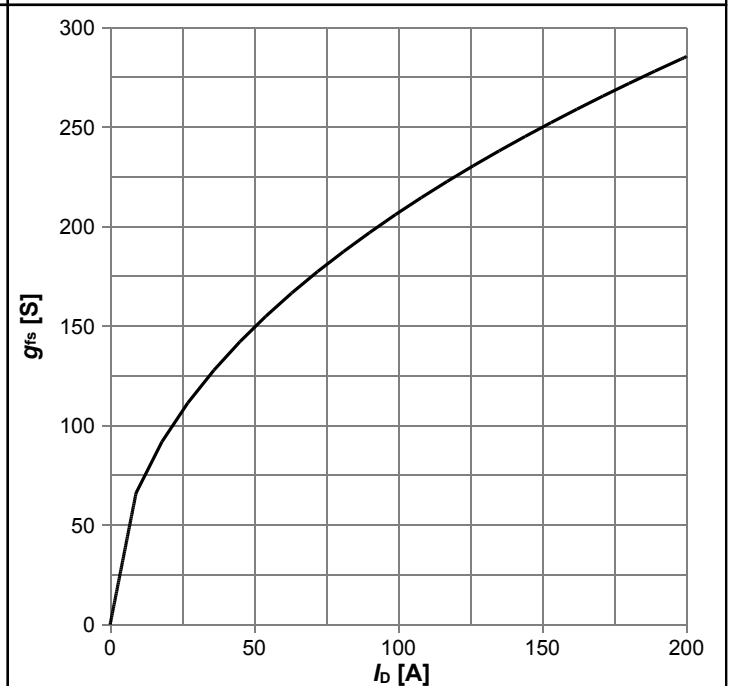
$R_{DS(on)} = f(I_D); T_j = 25\text{ °C};$  parameter:  $V_{GS}$

Diagram 7: Typ. transfer characteristics



$I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max};$  parameter:  $T_j$

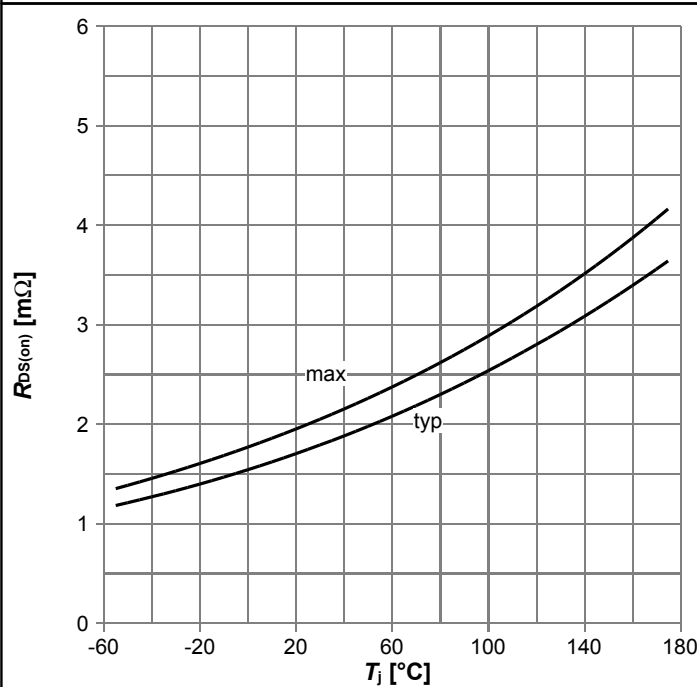
Diagram 8: Typ. forward transconductance



$g_{fs} = f(I_D); T_j = 25\text{ °C}$

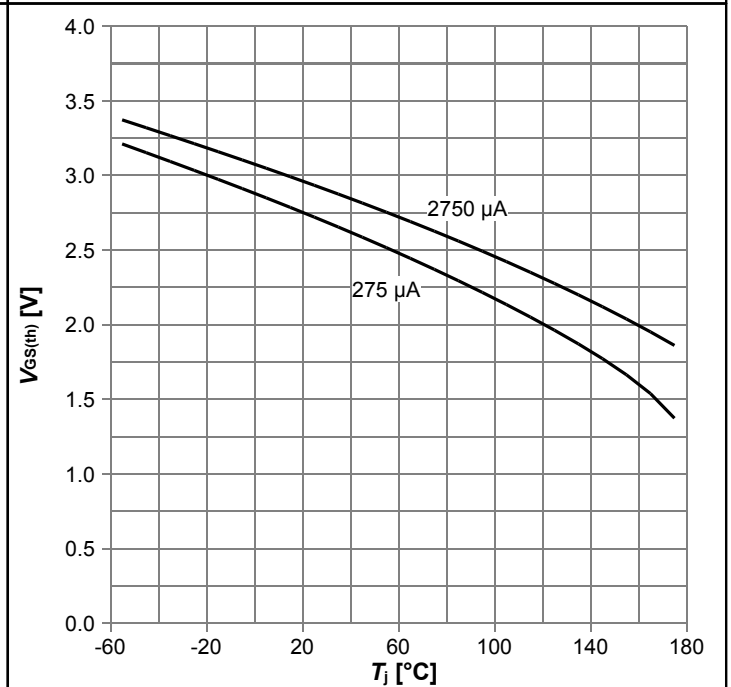


Diagram 9: Drain-source on-state resistance



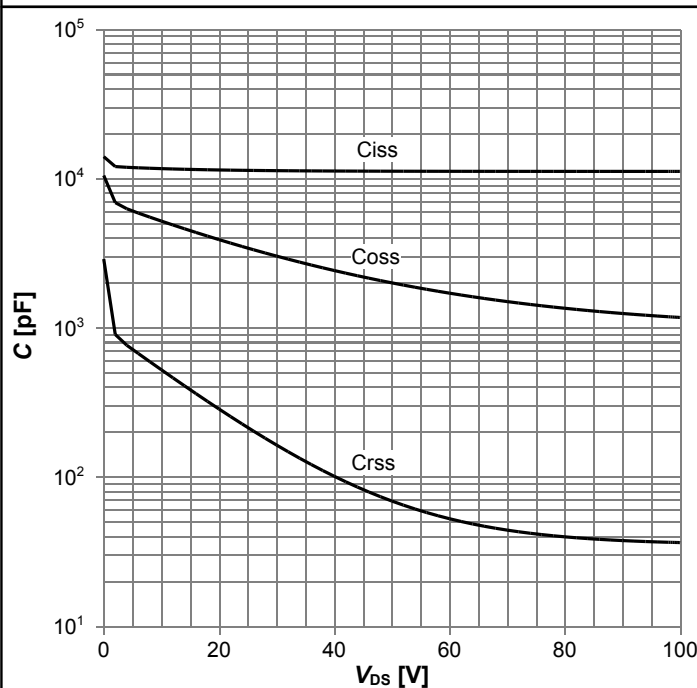
$R_{DS(on)}=f(T_j); I_D=150\text{ A}; V_{GS}=10\text{ V}$

Diagram 10: Typ. gate threshold voltage



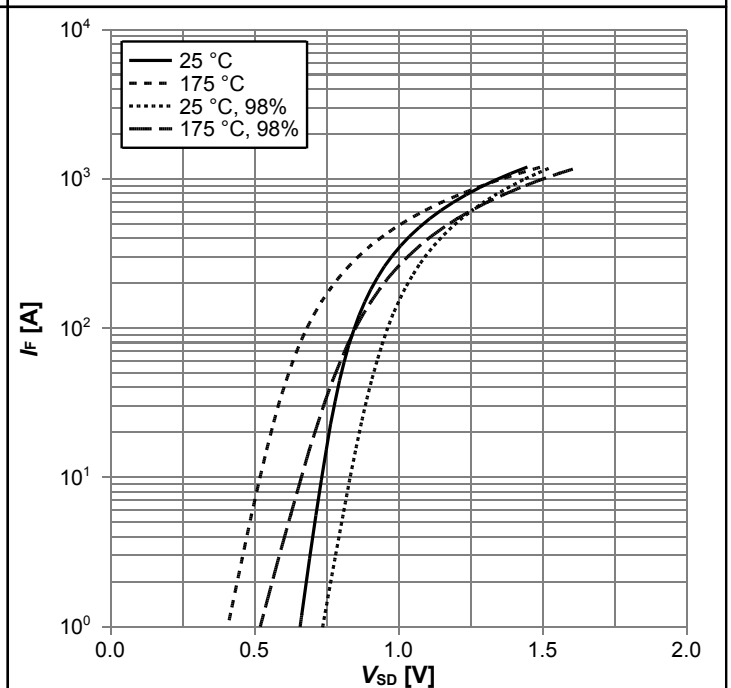
$V_{GS(th)}=f(T_j); V_{GS}=V_{DS}; \text{parameter: } I_D$

Diagram 11: Typ. capacitances



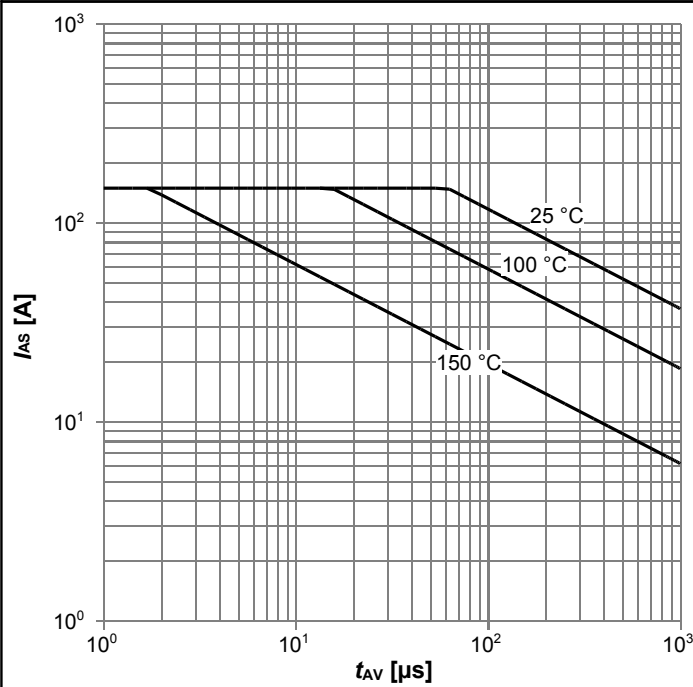
$C=f(V_{DS}); V_{GS}=0\text{ V}; f=1\text{ MHz}$

Diagram 12: Forward characteristics of reverse diode



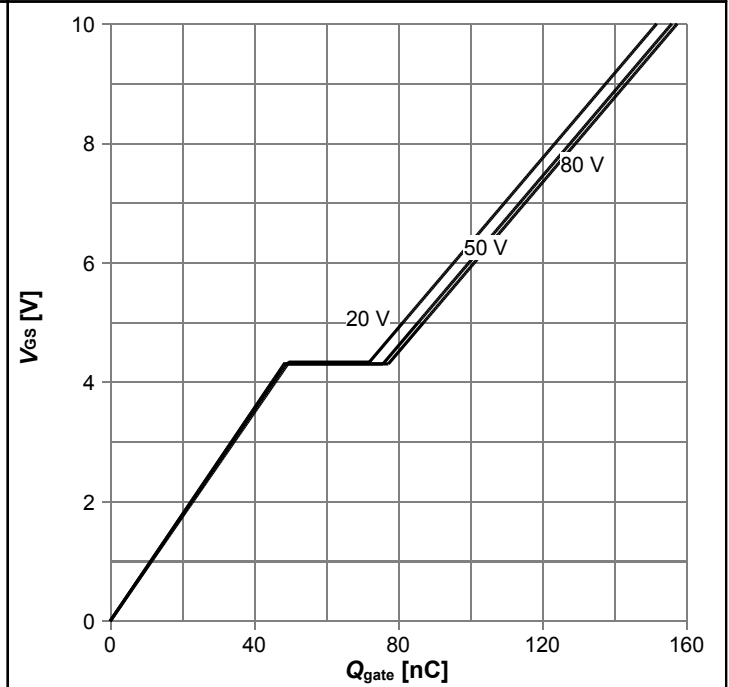
$I_F=f(V_{SD}); \text{parameter: } T_j$

Diagram 13: Avalanche characteristics



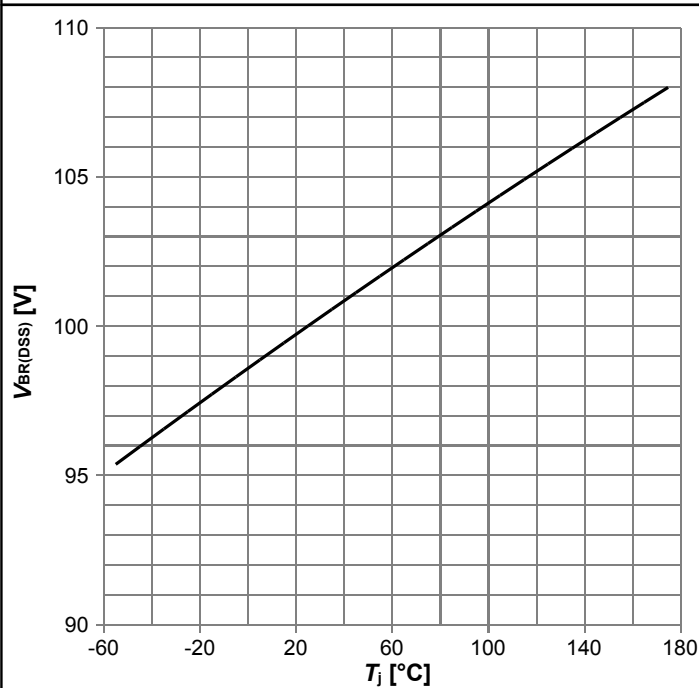
$I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$ ; parameter:  $T_{j(start)}$

Diagram 14: Typ. gate charge



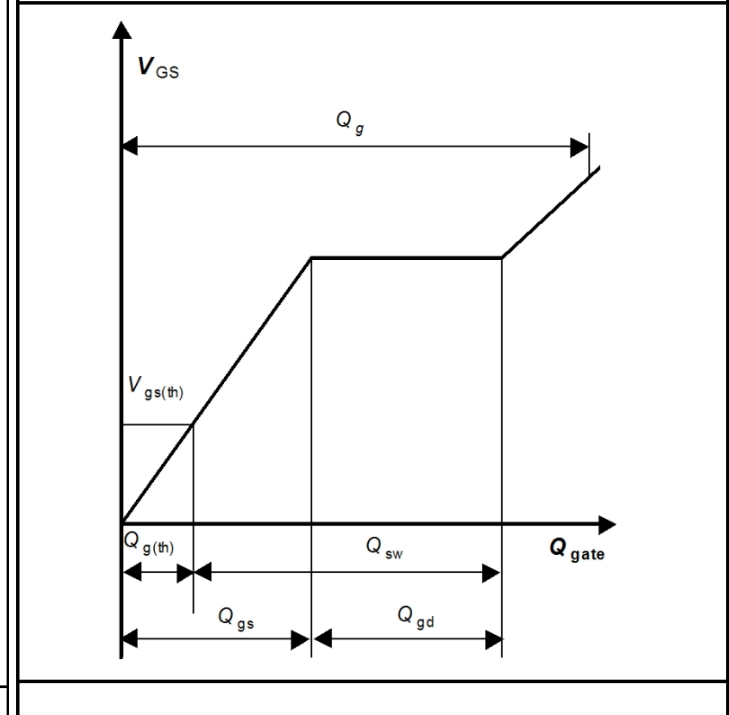
$V_{GS}=f(Q_{gate}); I_D=100$  A pulsed; parameter:  $V_{DD}$

Diagram 15: Drain-source breakdown voltage

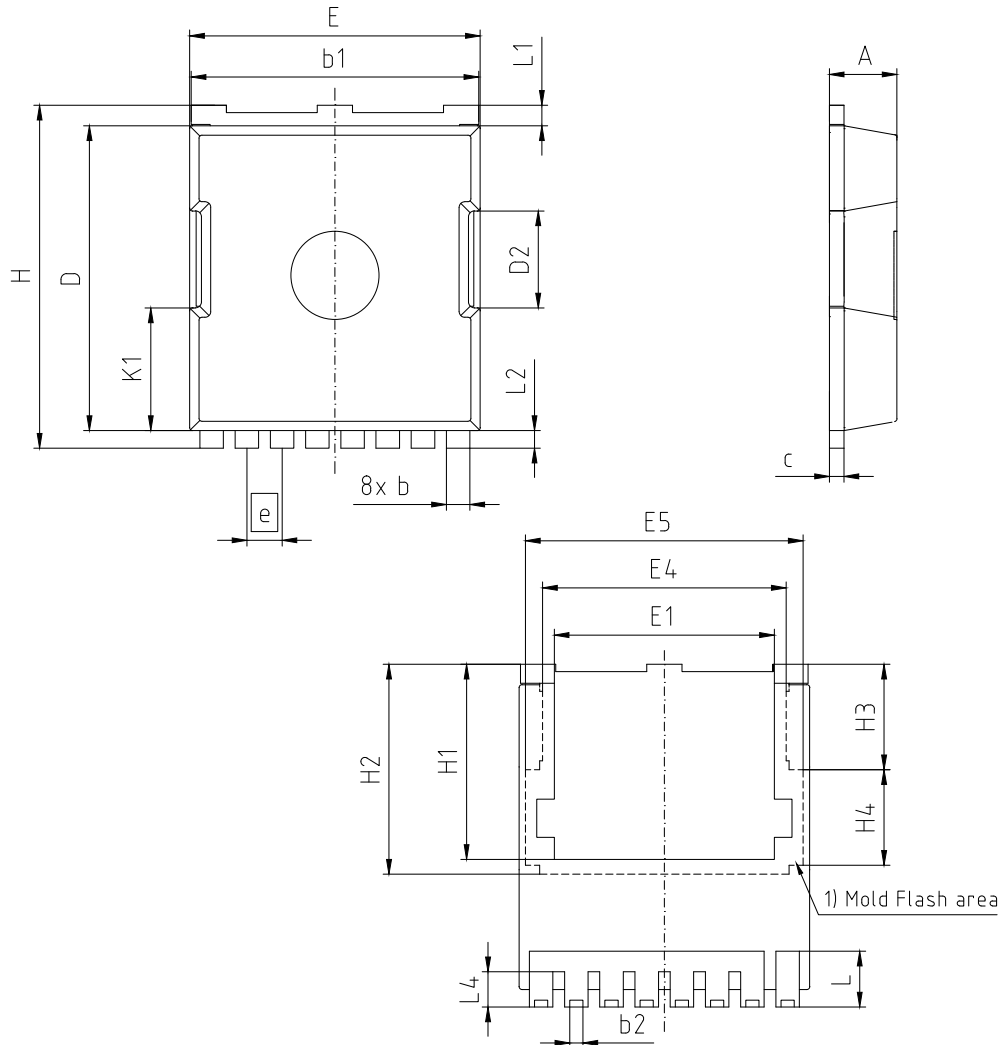


$V_{BR(DSS)}=f(T_j); I_D=1$  mA

Gate charge waveforms



## 6 Package Outlines



1) partially covered with Mold Flash

| DIM | MILLIMETERS |       | INCHES      |       |
|-----|-------------|-------|-------------|-------|
|     | MIN         | MAX   | MIN         | MAX   |
| A   | 2.20        | 2.40  | 0.087       | 0.094 |
| b   | 0.70        | 0.90  | 0.028       | 0.035 |
| b1  | 9.70        | 9.90  | 0.382       | 0.390 |
| b2  | 0.42        | 0.50  | 0.017       | 0.020 |
| c   | 0.40        | 0.60  | 0.016       | 0.024 |
| D   | 10.28       | 10.58 | 0.405       | 0.416 |
| D2  | 3.30        |       | 0.130       |       |
| E   | 9.70        | 10.10 | 0.382       | 0.398 |
| E1  | 7.50        |       | 0.295       |       |
| E4  | 8.50        |       | 0.335       |       |
| E5  | 9.46        |       | 0.372       |       |
| e   | 1.20 (BSC)  |       | 0.047 (BSC) |       |
| H   | 11.48       | 11.88 | 0.452       | 0.468 |
| H1  | 6.55        | 6.75  | 0.258       | 0.266 |
| H2  | 7.15        |       | 0.281       |       |
| H3  | 3.59        |       | 0.141       |       |
| H4  | 3.26        |       | 0.128       |       |
| N   | 8           |       | 8           |       |
| K1  | 4.18        |       | 0.165       |       |
| L   | 1.60        | 2.10  | 0.063       | 0.083 |
| L1  | 0.50        | 0.90  | 0.020       | 0.035 |
| L2  | 0.50        | 0.70  | 0.020       | 0.028 |
| L4  | 1.00        | 1.30  | 0.039       | 0.051 |

|                             |
|-----------------------------|
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| SCALE<br>0 2 4mm            |
| EUROPEAN PROJECTION<br>     |
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| REVISION<br>01              |

Figure 1 Outline PG-HSOF-8-1, dimensions in mm/inches

## Revision History

IPT020N10N3

**Revision: 2014-02-17, Rev. 2.0**

Previous Revision

| Revision | Date       | Subjects (major changes since last revision) |
|----------|------------|--|
| 2.0      | 2014-02-17 | Release of final version                     |

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